

**Search Notes**

Application/Control No.

10/766,974

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

SCHEUER ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	14, 27, 40, 129-132	5/25/2006	JDS
372	94	5/25/2006	JDS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
USPGPUB interference search -- see attached EAST search hist		5/25/2006	JDS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	5/25/2006	JDS
IEEE and INSPEC: radial, bragg grating	5/25/2006	JDS
USPGPUB interference search -- see attached EAST search history	5/25/2006	JDS